

A GLAST Analysis

<u>Agenda</u>

- Overarching Approach & Strategy
- Flattening Analysis Variables
- Classification Tree Primer
- Sorting out Energies
- PSF Analysis
- Background Rejection
- Assessment





Strategy

Terminology and GLAST Phase space: Light Gathering Power: $A_{eff} \times \Delta \Omega$

 $\begin{array}{rcl} GLAST S.R.: & 8000 \ cm^2 \times 2.0 \ str &= 16000 \ cm^2 - str \\ Goal: & 10000 \ cm^2 \times 2.4 \ str &= 24000 \ cm^2 - str \\ Triggerable: & 19630 \times .65 \times 2.4 \ str &= 30600 \ cm^2 - str \\ EGRET: & 1000 \ cm^2 \times .6 \ str &= 600 \ cm^2 - str \end{array}$

Input Data:

All Gamma: 18 MeV - 18 GeV into 6 m² x 2π str (= 37.7 m²-str) Energy Spectrum: 1/E (Flat in Log(E)) "Pre-Cuts": AcdActiveDist < -20 mm & TkrNumTracks > 0 Background: Generic On-Orbit Mix - same A_{eff} x ΔΩ

Variables:

To cover GLAST Phase space - make variables independent of Energy and cos(θ) Alternative: make analysis "cuts" energy and angle dependent

Key Methodology: Classification Trees





Strategy 2

Game Plan:

- 1) Flatten important variables used in the analysis
- 2) Use CT technology to determine events with "well measured" energies
- 3) Use CT technology to determine events with "well measured" directions
- 4) Filter background events (BGE's) and γ 's through the above CT scripts and form training and testing samples for background rejection
- 5) Use CT technology to separate γ 's from BGE's



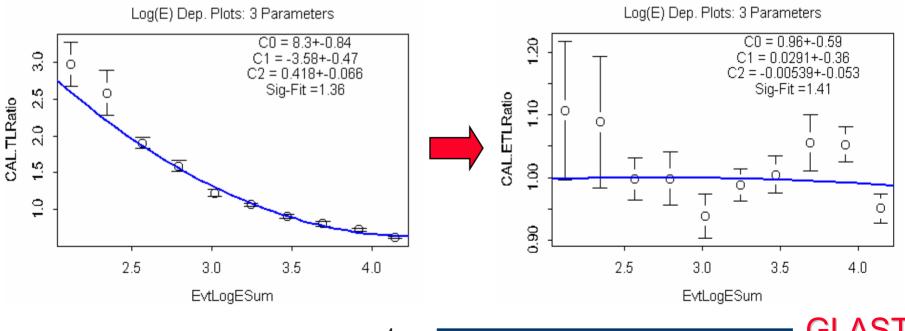
Flattening the Variables

Many analysis variables vary (albeit) slowly with energy and $cos(\theta)$.

Assume averages can be modeled by $\langle v_i \rangle = f(\log(E)) \cdot g(\cos(\theta))$

Least Squares Fit to 2nd order. First do *log(E)* dependence:

 $f(\log(E)) = c_0 + c_1 \cdot \log(E) + c_2 \cdot \log(E)^2$



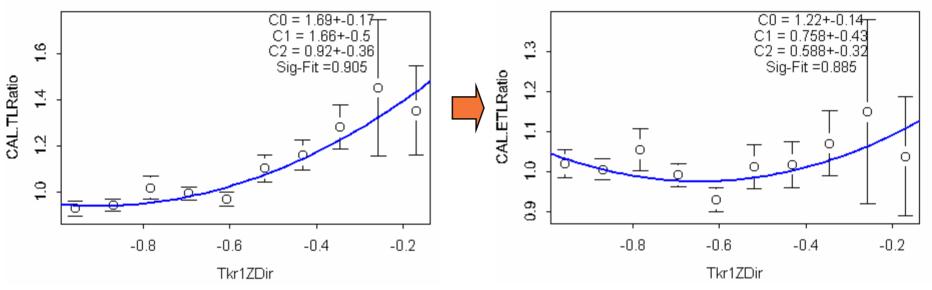


Flatten 2

Next do $\cos(\theta)$: $g(\cos(\theta)) = c_0 + c_1 \cdot \cos(\theta) + c_2 \cos(\theta)^2$

Cos(Theta) Dep. Plots: 3 Parameters

Cos(Theta) Dep. Plots: 3 Parameters



Variables which have been "flattened" include:

Tkr1Chisq Tkr2Chisq EvtTkrComptonRatio EvtCalXtalTrunc Tkr1FirstChisg Tkr2FirstChisg EvtCalTLRatio EvtCalTrackDoca Tkr1Qual Tkr2Qual **EvtCalXtalRatio** EvtCalTrackSep EvtVtxEAngle EvtVtxDoca EvtVtxHeadSep (il

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Classification Tree Primer

Origin: Social Sciences - 1963

How a CT works is simple: A series of "cuts" parse the data into a "tree" like structure where final nodes (leaves) are "pure"

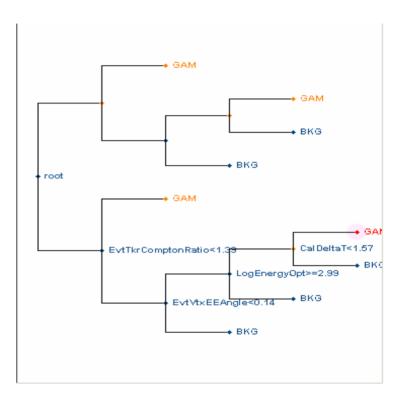
How the Cuts are determined is harder: (Called Partitioning) Total Likelihood for a tree is:

$$L = \prod_{i-leaves} \prod_{k-classes} p_{ik}^{n_{ik}}$$

where p_{ik} are the probabilities and n_{ik} are the number of events. For each node define a deviance

$$D_i = -2\sum_{k-classes} n_{ik} \log(p_{ik})$$

Splitting node *i* into two smaller nodes s & t Results in a reduction in deviances given by



$$D_s - D_t - D_u = 2 \sum_{k-classes} \left[n_{tk} \log(\frac{p_{tk}}{p_{sk}}) + n_{uk} \log(\frac{p_{uk}}{p_{sk}}) \right]$$

where $n_{sk} = n_{tk} + n_{uk}$



Tree Primer (2)

The probabilities are not know *a priori* so the event counts in the training sample are used.

Example:
$$\widetilde{p}_{tk} = \frac{n_{tk}}{n_t}$$

From this the value of a split can be determined by
 $D_s - D_t - D_u = 2 \left[\sum_{k-classes} (n_{tk} \log n_{tk} + n_{uk} \log n_{uk} - n_{sk} \log n_{sk}) + n_s \log n_s - n_t \log n_t - n_u \log n_u \right]$

Note that splitting nodes with large numbers of events is favored.

Splitting of each node continues until change in deviance is too small or the number of events in the node has fallen below a minimum.

Tree construction is a "look one step ahead" process - it does not necessarily find the ultimate optimal tree.

Trees readily adapt to the "training" data if the event count in the leaves or the deviance reduction at each split is allowed to be too small.





Sorting Out the Energies

Energy Types:

Percentages:

1)	No CAL Events: < 5 MeV OR < 2 r.l. in CsI	46%
2)	Low CAL Events: < 100 MeV	13%
3)	High CAL Events: > 100 MeV	41%

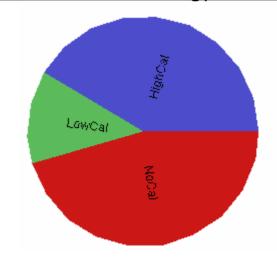
Good Energy Definition

Model: $\frac{\Delta E}{E} = \frac{E_{Obs} - E_{MC}}{.8E_{MC} + 40MeV}$

(Maps energy errors onto a common scale. Example: for σ_{Energy} = .1 (GLAST Nominal) $\Delta E_{100 \text{ MeV}}$ = 12 MeV & $\Delta E_{1000 \text{ MeV}}$ = 84 MeV)

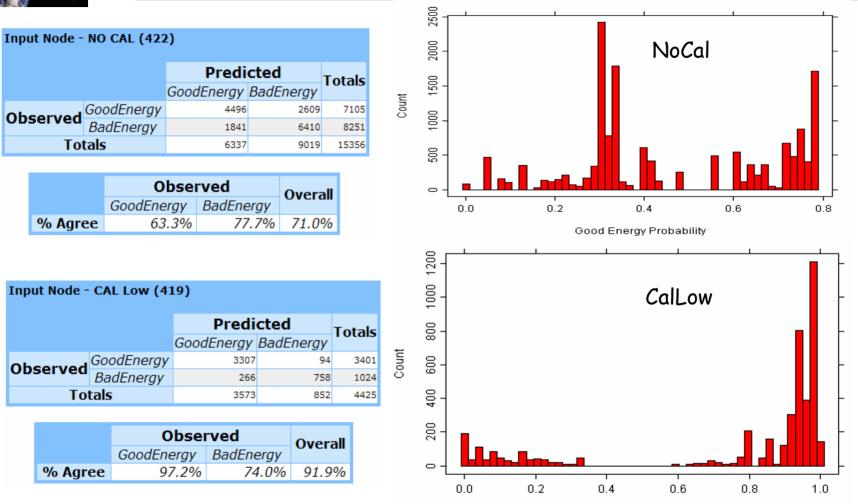
No CAL: -.4 < △E/E < 1.5 (-60% + 150%) Low/Hi CAL: -.5 < △E/E < .5 (+- 50%)

Break Down of Energy Classes



Energy Classes

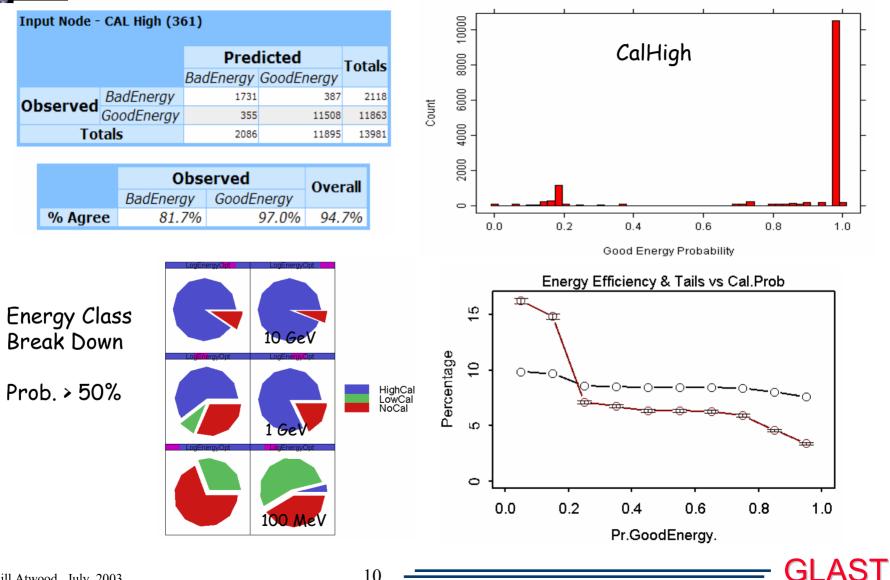




Good Energy Probability

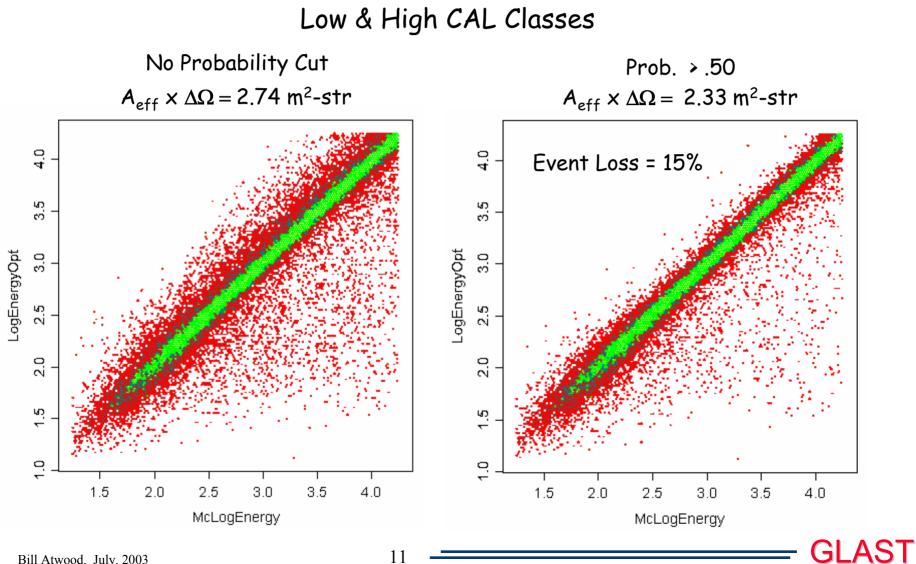
GLAST

Energy Classes





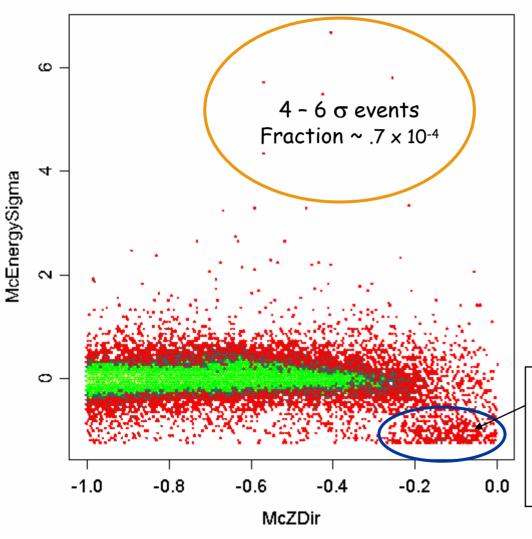
Energy Summary



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Energy Summary (cont')



Energy is "FLAT" in dimensions of θ and E.

Remaining $A_{eff} \times \Delta \Omega = 2.33 \text{ m}^2\text{-str}$

Remaining "Bad Energy": 6.3%

Remaining "Good Energy": 84%

Horizontal Events - Not so easy to remove at this stage. Note: This is where they are generated - NOT where they are reconstructed





PSF Analysis



Maintain the highest $A_{\rm eff} \times \Delta \Omega$

Provide a "tune-able" handle to improve resolution allowing for flexibility in applications to science topics

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(667)

Predict: NO CA1 (666)

(66.3)

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Ple Chart (662)

Rows (57)

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Histogram (S70)

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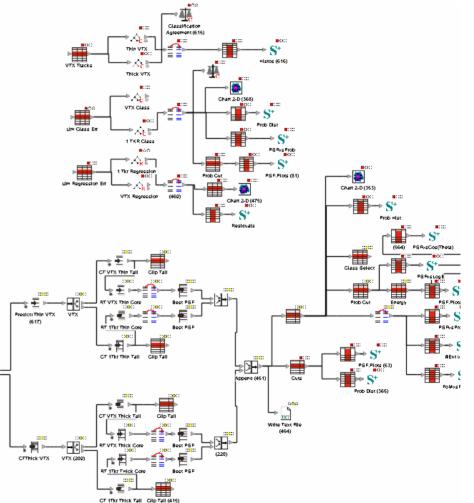
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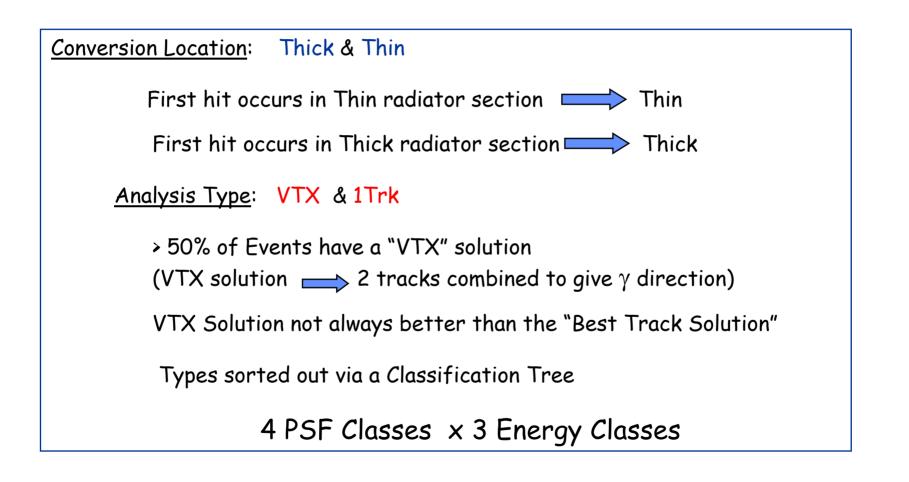
GLAST

Input Tuple (65

TKR Energy (660) Energy (6



PSF Classes





The VTX Decision

	•	-		
		Predicted		Totale
		1TKR	VTX	Totals
Observed	1TKR	1595	1277	2872
Observed	VTX	503	4031	4534
Totals		2098	5308	7406

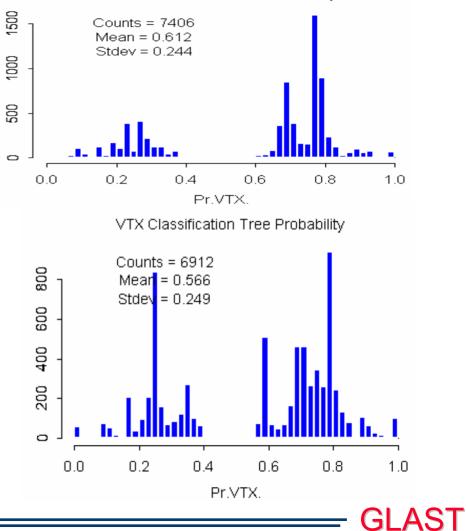
Input Node - Thin VTX (259)

	Obse	Overall		
	1TKR	VTX	overail	
% Agree	55.5%	88.9%	76.0%	

Input Node - Thick VTX (259)				
		Predicted		Totals
		1TKR	VTX	TUTAIS
Observed	1TKR	1843	1159	3002
Observed	VTX	622	3288	3910
Totals		2465	4447	6912

	Observed		Overall	
	1TKR	VTX	overun	
% Agree	61.4%	84.1%	74.2%	

VTX Classification Tree Probability



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VTX Thin



Input Node - (231)

		Predicted		Totals
		CORE	TAIL	····
Observed	CORE	4569	81	4650
	TAIL	154	485	639
Totals		4723	566	5289

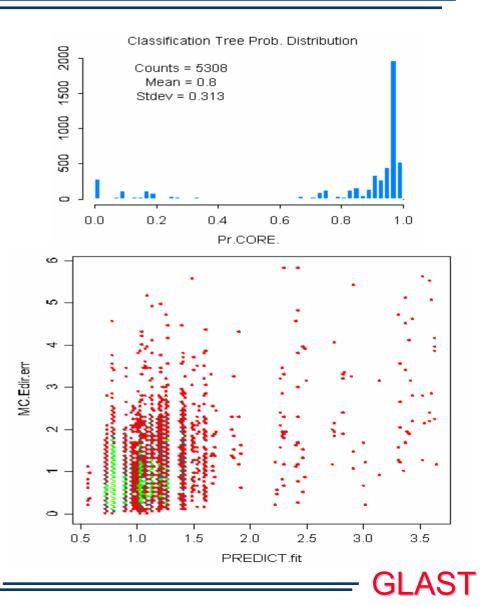
	Obse	Overall		
	CORE	TAIL	Overail	
% Agree	98.3%	75.9%	95.6%	

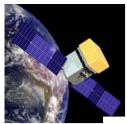
Clip Bad Events using a CT

Predict how "good" using a

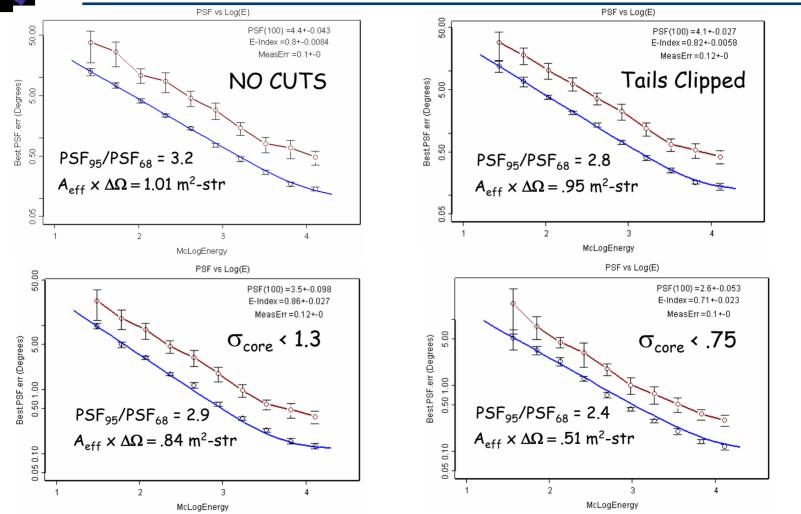
Regression Tree

This process is repeated for the 4 Tracking Event Classes

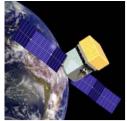




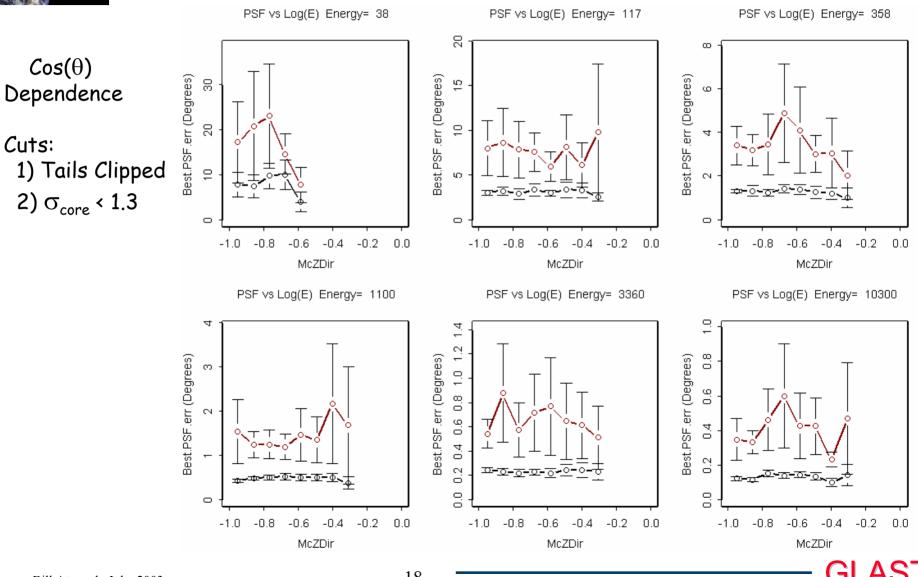
PSF Results – Thin Radiator



GLAST



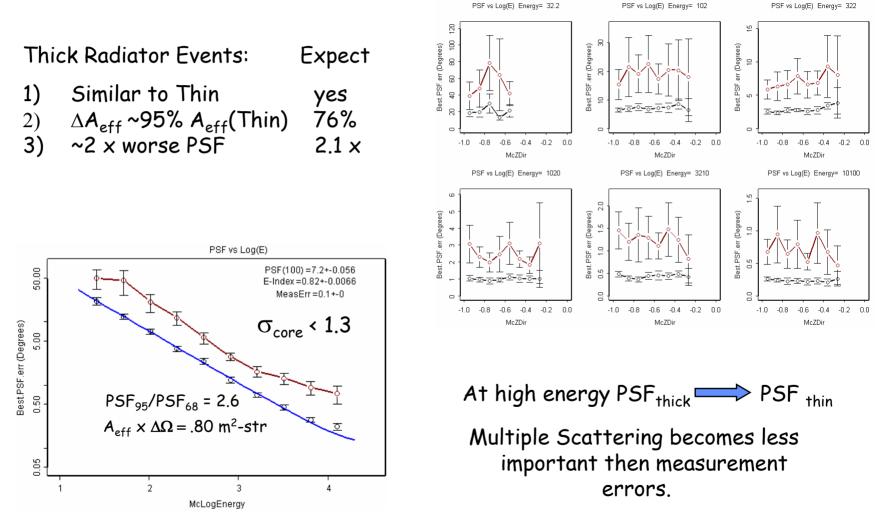
Thin Radiator PSF 2



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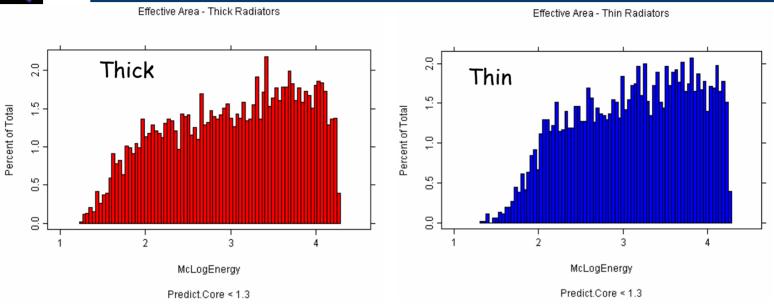
PSF Results – Thick Radiator



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PSF Results – What Remains



 $A_{eff} \times \Delta \Omega$ distributions approximately the same

SR case ($\sigma_{core} < 1.3$): $A_{eff} \times \Delta \Omega = .80 \text{ m}^2 \text{-str} + .84 \text{ m}^2 \text{-str} = 1.64 \text{ m}^2 \text{-str}$ Ratio of Integral log(E) plots to flat (as generated) distribution: ~ 1.8 Hence Asymptotic $A_{eff} \times \Delta \Omega = 2.94 \text{ m}^2 \text{-str}$ (lots of light gathering power left)

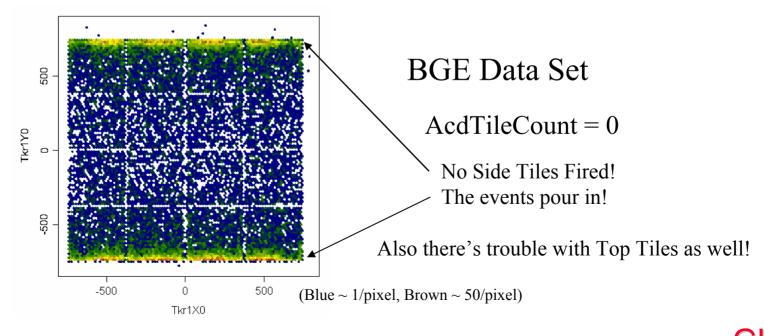


Background Rejection

Goal: remove most of the BGE's while preserving the γ signal

Problem: Large imbalance between #BGE's and # γ 's. CT's need sufficient #'s of events to establish unbiased model trees.

Show Stopper: 11th hour discovery of problems in ACD Sim & Analysis





Forge Anead! (DIFSA)

The Formal portion of the talk is now ended!

What lies ahead is presented to show the direction which is being pursued.

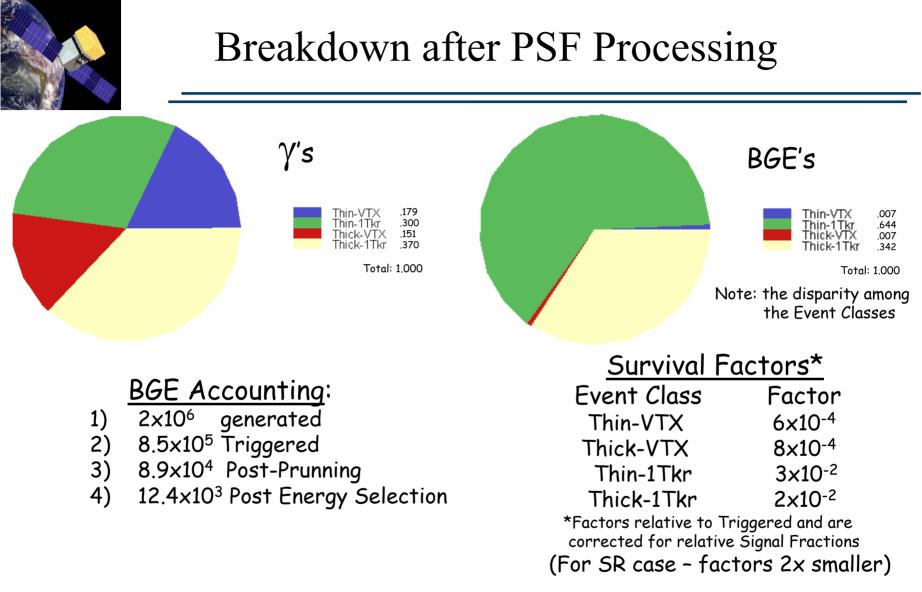
All the quantitative results are given as illustrative only!

IN SHORT: QUOTE NOTHING FROM THIS!

Step 1:

Events are first processed in the PSF Analysis script. a) Good Energy Prob. > .50 b) Determine Event Classes c) Compute CT's for PSF Analysis d) No cuts on PSF - goodness





At this point γ events have lost 4% due to ACD cuts & 15% due to energy cut

Losses: minimal and the VTX Event Classes already have S/N ~ 1:1!



BGE Rejection CT's

Step 2:

Mixes of BGE's and γ 's are formed

a) Training Sample - 50:50 BGE:γ (Split the BGE sample 50:50 Training/Testing)

- Leaves only ~ 6500 of each type
- Statistics allow for only shallow CT's
- For demonstration Lump Thick & Thin Event Classes Together

b) Test Sample - 80:1 BGE: γ (relative to "as-generated" totals)

The available statistics don't even allow for this!

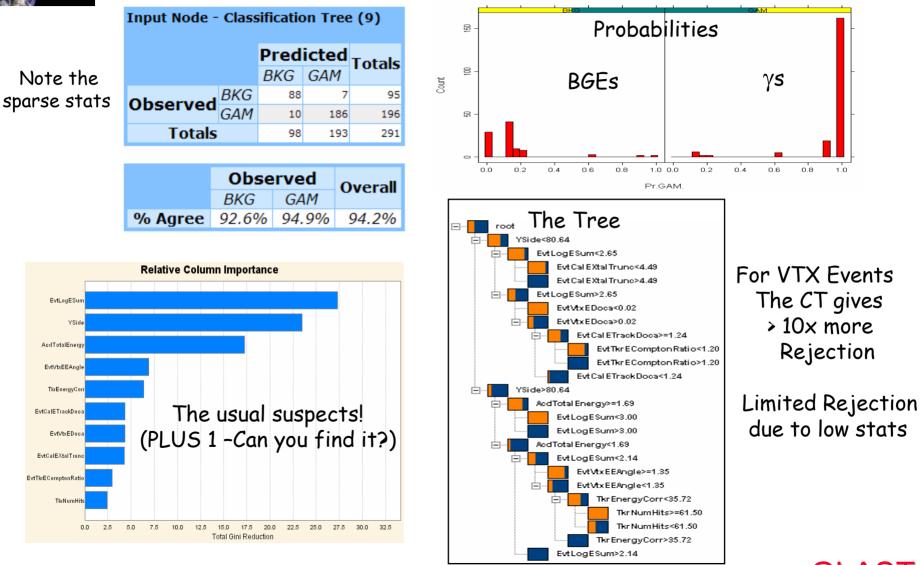
- Leaves only ~ 500 γ 's (after SR Case PSF Cuts ~ 400 γ 's)

Caveat: What ratio of events should the train sample have?

- Need sufficient numbers of both classes to establish patterns
- At "real" analysis ratios the CT splitting mechanism work poorly. Deviance per split will be too small.
- Trial & Error shows that ratio needs to be within a factor of 2.



BGE Rejection CT's: VTX Events

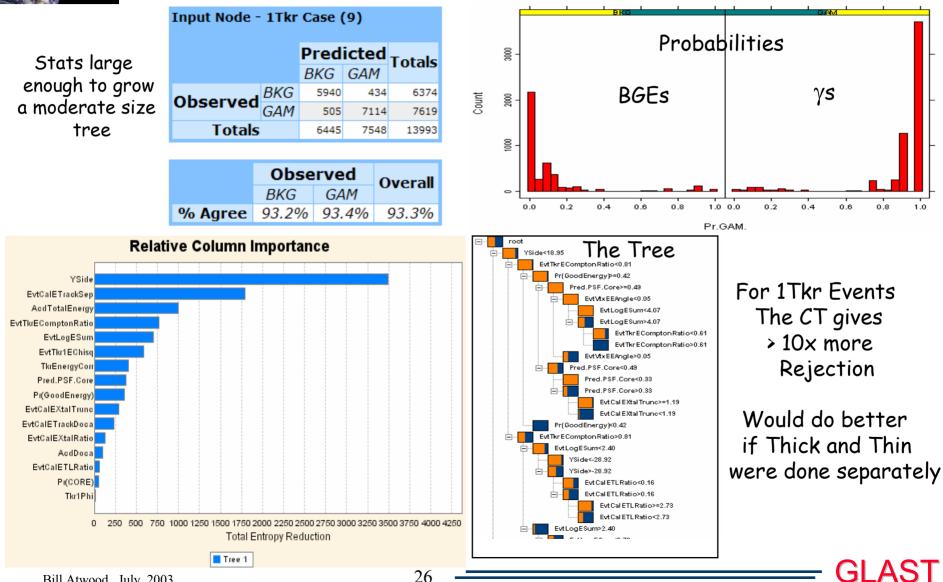


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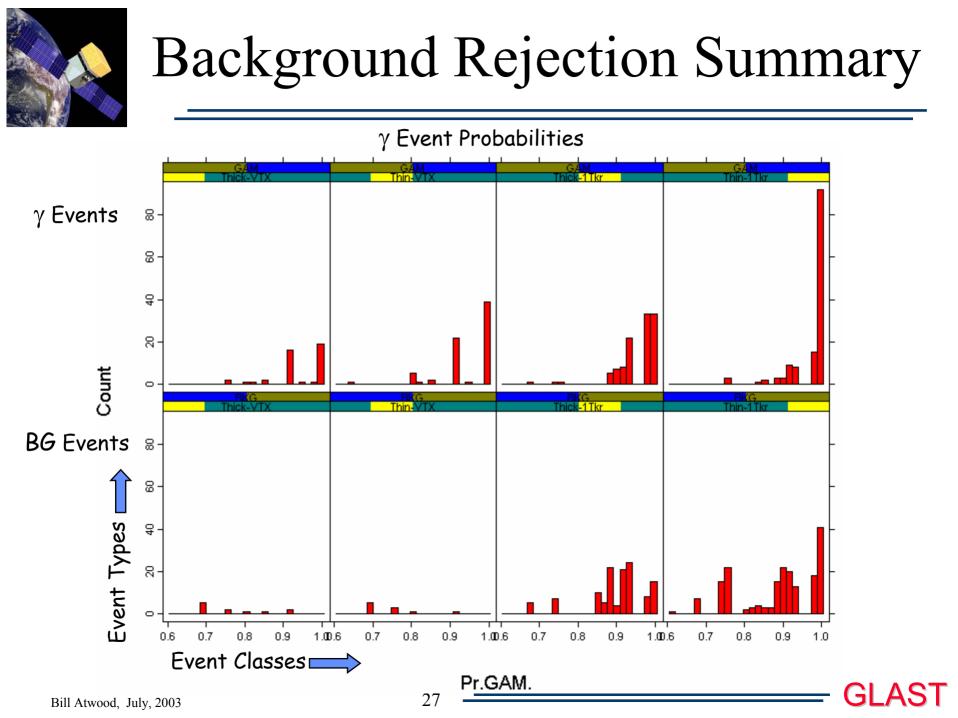
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BGE Rejection CT's: 1Trk Events



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BGE Rejection Summary 2

VTX Events (undifferentiated w.r.t. Thin/Thick)

- 1) Remaining background: 3% (But recall test sample is only 80:1)
- 2) Good Event Loss: 17%
- 3) BGE Reduction Factor: 16x (post SR Case selection)
- 4) Further progress stop for lack of statistics (there were 3 BGE's events left)

<u>1Tkr Events</u> (undifferentiated w.r.t. Thin/Thick)

- 1) Remaining background: 32% (No there yet!)
- 2) Good Event Loss: 3%
- 3) BGE Reduction factor: 60x (post SR case selection
- 4) Further progress limited by state of present software

This exercise is an example of what will happen to the science if we lose two sides of the ACD and put a big hole in the top of it as well!